

Strain mapping of nano-twinned axial ZnTe/CdTe hetero-nanowires

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The aim: The development of a method for precise high-resolution strain mapping of highly strained hetero-nanowires (NWs) with twin boundaries and high thickness gradient

Object: CdTe/ZnTe hetero-nanowires fabricated by molecular beam epitaxy (MBE) with the use of Au nano-catalysts

Instrument: Transmission electron microscope Titan Cubed 80–300 operating at 300 kV

The main challenges in ZnTe/CdTe NW strain mapping:

- high thickness gradient
- nano-twinning (for non-centrosymmetric zone axis)

Geometric Phase Analysis (GPA) nano-twinned axial ZnTe/CdTe hetero-nanowire

Require:	Limited field of view (FOV)	I ₍₋₁₁₋₁₎	I ₍₋₁₁₁₎ A Twin A	I ₍₁₋₁₋₁₎ B Twin B
 perfect zone axis orientation 	Difficult analysis in the case of nano-twinning			
	ZnTe CdTe	max	max	



Nano-beam electron diffraction (NBED)







electron beam. The measurements of the length of reciprocal lattice $|g_{hkl}| \sim \frac{1}{d_{hkl}}$ vector g for a particular reflection allows the determination of lattice spacing.



(CHT) with variable radius solves the problem of the variation of the disk radius



- We improved algorithm for the detection of the centers of diffraction disks based on the Sobel filtering and Hough transform.
- Proposed methodology of NBED strain mapping for NW which is characterized by a high gradient of thickness and composition.
- We show that it is possible to determine the 3D strain distribution in elastically strained axial NW based on the experimental 2D maps of the lattice distortion and 3D FEM simulations (with assumption the radial symmetry of NW).

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